

Date Created : 2009/06/11
 Date Issued On : 2009/07/14
 PCN# : Q2092402

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

Technical Contact:
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PCN Originator:
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Implementation of change:
 Expected 1st Device Shipment Date: 2009/10/12

Earliest Year/Work Week of Changed Product: 0942

Change Type Description: Alternate Fab Location

Description of Change (From): LED die supply from Fairchild Singapore Foundry

Description of Change (To): LED die supply for these products will now be fabricated by a foundry in Japan.

Reason for Change : Establish an alternate die source.

Qual/REL Plan Numbers : Q20090131

Qualification :

Passed all tests.

Results/Discussion for Qual Plan Number Q20090131

Test: (High Temperature Op Life) Conditions: 100C Standard:						
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	2000	Failure Code
Q20090131AAHTOL	FODM453	0/45				
			0/45			
				0/45		
					0/45	
Q20090131ABHTOL		0/45				
			0/45			
				0/45		
					0/45	
Q20090131ACHTOL		0/45				

			0/45		
				0/45	
					0/45
Test: (High Temperature Storage Life) Conditions: 150C Standard: JESD22-A103					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20090131AAHTSL		0/45			
			0/45		
				0/45	
Q20090131ABHTSL		0/45			
			0/45		
				0/45	
Q20090131ACHTSL		0/45			
			0/45		
				0/45	
Test: (Power Cycle) Conditions: Delta 100CC, 2 Min cycle Standard: MIL-STD-750-1036					
Lot	Device	5000-CYCLES	10000-CYCLES	15000-CYCLES	Failure Code
Q20090131AAPRCL		0/45			
			0/45		
				0/45	
Q20090131ABPRCL		0/45			
			0/45		
				0/45	
Q20090131ACPRCL		0/45			
			0/45		
				0/45	
Test: (Precondition) Conditions: Standard: JESD22-A113					
Lot	Device	Results			Failure Code
Q20090131AAPCOPTO1B	FODM453	0/180			
Q20090131ABPCOPTO1B	FODM453	0/180			
Q20090131ACPCOPTO1B	FODM453	0/180			
Test: (Temperature Cycle) Conditions: -40C, 125C Standard: JESD22-A104					
Lot	Device	100-CYCLES	200-CYCLES	500	Failure Code
Q20090131AATMCL2		0/45			
			0/45		
				0/45	
Q20090131ABTMCL2		0/45			
			0/45		
				0/45	
Q20090131ACTMCL2		0/45			
			0/45		
				0/45	
Test: (Temperature Humidity Biased Test) Conditions: 85%RH, 85C, 4V Standard: JESD22-A101					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20090131AATHBT		0/45			
			0/45		
				0/45	
Q20090131ABTHBT		0/45			
			0/45		
				0/45	
Q20090131ACTHBT		0/45			
			0/45		
				0/45	

Product Id Description : 5-pin mini flat package high speed phototransistor optocoupler

Affected FSIDs :

FODM452R1V	FODM452R1	FODM452R2V
FODM452R2	FODM452V	FODM452
FODM453R1V	FODM453R1	FODM453R2V
FODM453R2	FODM453V	FODM453